FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)

ATTY DOCKET NO. 03500.017976

APPLICATION NO. 10/806,157

APPLICANT Tetsuro NAKAMURA et al.

August 30, 2004			FILING DATE March 23, 2004		GROUP 1753	
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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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